LXI Consortium Announces New Resources for Engineers Applying LXI Technology

Niwot, Colo. – February 2, 2010

What: Two new resources are available to help engineers keep pace with the latest in LXI technology for switching systems, ATE systems, and other test instruments:

- **Article: LXI vs. PXI in Switching Applications.** A new article by David Owen of Pickering Interfaces was published in the January 2010 issue of *Evaluation Engineering* magazine. The article has case histories and gives selection advice on the two most common platforms for switching systems, PCI eXtensions for Instrumentation (PXI) and LAN eXtensions for Instrumentation (LXI). Larger switching systems, particularly matrices, are more easily accommodated by the unrestricted size of an LXI instrument than by one or more PXI or VXI modules. Especially for a matrix that is intended to operate as a single unit, splitting the hardware among several chassis makes programming awkward, and the additional external electrical connections adversely affect high-frequency performance.

- **Webcast: How to Create Advanced ATE Systems with LXI – Building on the Industry's Best Practices.** This recently archived webcast is moderated by Rick Nelson, Editor in Chief, *Test & Measurement World* and *EDN*. What are the advantages of putting test systems online? What is the difference between LAN (Local Area Network) and LXI (LAN
eXtensions for Instrumentation) instruments? How does LXI work with my existing equipment? This webcast answers these questions with help from a distinguished panel from the LXI Consortium.

When: Available now

Where: Download article at:

View webcast at:
https://event.on24.com/eventRegistration/EventLobbyServlet?target=registration.jsp&eventid=159532&sessionid=1&key=8444DB87CB4DB1E9FF457A0A6FA31FC7&partnerref=tmwwbcstpg&sourcepage=register

Additional Information: www.lxistandard.org

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NOTE TO EDITORS: Further information is available at www.lxistandard.org